

Search Notes

Application/Control No.

10/814,369

Examiner

/Yonel Beaulieu/

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

3661

SEARCHED

| Class | Subclass | Date | Examiner |
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| 701 | 3 | 5/30/2007 | YB |
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| 244 | 158.1 | | |
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| 340 | 945 | | |
| 702 | 144 | | |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| WEST | 5/30/2007 | YB |
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